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US Patent & Trademark Office: U.S. DEPARTMENT OF COMMERCE

Substitute for form 1449A/PTO Complete if Known INFORMATION DISCLOSURE **Application Number** 09/945,535 STATEMENT BY APPLICANT (Use of Pan Cheety Boocessary) Filing Date August 30, 2001 Ahn, Kie **First Named Inventor** OCT 2 6 2005 2813 **Group Art Unit Examiner Name** Blum, David Attorney Docket No: 1303.026US1

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OPE WAR	First Named Inventor	Ahn, Kie
- 1	Group Art Unit	2813
OCT 2 6 2005 H	Examiner Name	Blum, David
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